Search Notes



Application/Control No.	Applicant(s)/Patent Under
•	Reexamination

Reexamination
10629842 YOSHIKAWA ET AL.

Examiner

Kiss, Eric B

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
717	174	03/22/2007	EBK
719	327	03/22/2007	EBK
710	313	03/22/2007	EBK

SEARCH NOTES			
Search Notes	Date	Examiner	
PALM Inventor search	03/22/2007	EBK	
EAST (USPAT; US-PGPUB; EPO; JPO; FPRS; DERWENT; IBM_TDB) (see search history printout)	03/22/2007	EBK	
updated EAST search (see search history printout)	09/04/2007	EBK	

INTERFERENCE SEARCH			
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